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U.S. UTILITY Patent Application

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APPLICATION NO. CONT/PRIOR CLASS SUBCLASS ART UNIT **EXAMINER** 09/997134 356-2877 Richard Odom Robert Wilson TSAI

Apparatus and methods for measurement of density of materials using a neutron source and two spectrometers

/ ISSUING CLASSIFICATION								
/ ORIGINAL ⁴			CROSS REFERENCE(S)					
CLASS SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
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INTERNATIONAL CLASSIFICATION								
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TERMINAL	DRAWINGS			CLAIMS ALLOWED	
L.J DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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has been disclaimed.	(Assistant Examiner)		(Date)		
☐ The term of this patent shall	!			-	
not extend beyond the expiration date of U.S Patent. No				ISSUE FEE	
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	(Primary	Examiner)	(Date)		
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